DATA SHEET 74F27 Triple 3-input NOR gate **Product specification** 1991 Feb 05 IC15 Data Handbook

INTEGRATED CIRCUITS







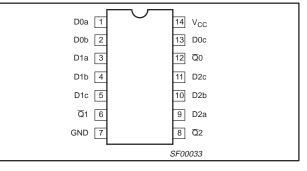
74F27

FEATURE

• Industrial temperature range available (-40°C to +85°C)

TYPE	TYPICAL PROPAGATION DELAY	TYPICAL SUPPLY CURRENT (TOTAL)
74F27	3.0ns	6.5mA

PIN CONFIGURATION



ORDERING INFORMATION

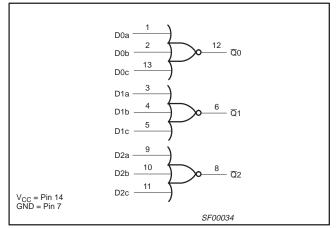
	C		
DESCRIPTION	COMMERCIAL RANGE V_{CC} = 5V ±10%, T_{amb} = 0°C to +70°C	INDUSTRIAL RANGE V_{CC} = 5V ±10%, T_{amb} = -40°C to +85°C	PKG DWG #
14-pin plastic DIP	N74F27N	I74F27N	SOT27-1
14-pin plastic SO	N74F27D	I74F27D	SOT108-1

INPUT AND OUTPUT LOADING AND FAN OUT TABLE

PINS	DESCRIPTION	74F (U.L.) HIGH/LOW	LOAD VALUE HIGH/LOW
Dna, Dnb, Dnc	Data inputs	1.0/1.0	20µA/0.6mA
Qn	Data output	50/33	1.0mA/20mA

NOTE: One (1.0) FAST unit load is defined as: 20µA in the high state and 0.6mA in the low state.

LOGIC DIAGRAM



FUNCTION TABLE

	OUTPUT		
Dna	Dnb	Dnc	Qn
L	L	L	Н
Х	Х	Н	L
Х	Н	Х	L
Н	Х	Х	L

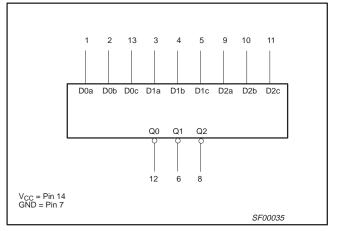
NOTES:

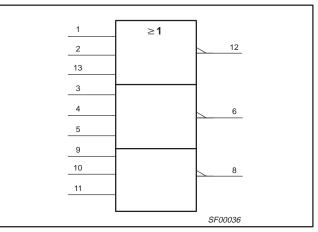
H = High voltage level

L = Low voltage level

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LOGIC SYMBOL





ABSOLUTE MAXIMUM RATINGS

(Operation beyond the limit set forth in this table may impair the useful life of the device. Unless otherwise noted these limits are over the operating free air temperature range.)

SYMBOL	PARAMETER		RATING	UNIT
V _{CC}	Supply voltage		-0.5 to +7.0	V
V _{IN}	Input voltage		-0.5 to +7.0	V
I _{IN}	Input current		-30 to +5	mA
V _{OUT}	Voltage applied to output in high output state		–0.5 to V_{CC}	V
I _{OUT}	Current applied to output in low output state		40	mA
.		Commercial range	0 to +70	°C
lamb	Operating free air temperature range Industrial range		-40 to +85	°C
T _{stg}	Storage temperature range		-65 to +150	°C

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER			UNIT		
			MIN	NOM	MAX	
V _{CC}	Supply voltage			5.0	5.5	V
V _{IH}	High–level input voltage					V
V _{IL}	Low-level input voltage				0.8	V
I _{lk}	Input clamp current				-18	mA
I _{OH}	High-level output current				-1	mA
I _{OL}	Low-level output current				20	mA
T _{amb}	Operating free air temperature range	Commercial range	0		+70	°C
		Industrial range	-40		+85	°C

IEC/IEEE SYMBOL

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DC ELECTRICAL CHARACTERISTICS

(Over recommended operating free-air temperature range unless otherwise noted.)

SYMBOL	DL PARAMETER		TEST CONDITIO	LIMITS			UNIT	
					MIN	TYP ²	MAX	
V _{OH}	High-level output voltage		$V_{CC} = MIN, V_{IL} = MAX$	±10%V _{CC}	2.5			V
			$V_{IH} = MIN, I_{OH} = MAX$	$\pm 5\% V_{CC}$	2.7	3.4		V
V _{OL}	Low-level output voltage		$V_{CC} = MIN, V_{IL} = MAX$	±10%V _{CC}		0.30	0.50	V
			$V_{IH} = MIN, I_{OI} = MAX$	$\pm 5\% V_{CC}$		0.30	0.50	V
V _{IK}	Input clamp voltage		$V_{CC} = MIN, I_I = I_{IK}$			-0.73	-1.2	V
I _I	Input current at maximum input vo	ltage	$V_{CC} = MAX, V_I = 7.0V$				100	μΑ
I _{IH}	High-level input current		$V_{CC} = MAX, V_I = 2.7V$				20	μΑ
IIL	Low-level input current		$V_{CC} = MAX, V_I = 0.5V$				-0.6	mA
I _{OS}	Short-circuit output current ³		$V_{CC} = MAX$		-60		-150	mA
I _{CC}	Supply current (total)	I _{CCH}	V _{CC} = MAX	$V_{IN} = GND$		4.0	5.5	mA
		I _{CCL}	$V_{CC} = MAX$	$V_{IN} = 4.5V$		8.5	12.0	mA

NOTES:

For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type. 1

2 All typical values are at $V_{CC} = 5V$, $T_{amb} = 25^{\circ}C$. 3 Not more than one output should be shorted at a time. For testing I_{OS} , the use of high-speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting of a high output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests, IOS tests should be performed last.

AC ELECTRICAL CHARACTERISTICS

			LIMITS							
SYMBOL	PARAMETER	TEST CONDITION	Ta	_{CC} = +5.0 _{mb} = +25 0pF, R _L =	°C	T _{amb} = 0°C	0V ± 10% C to +70°C R _L = 500Ω	$T_{amb} = -40^\circ$	0V ± 10% °C to +85°C R _L = 500Ω	UNIT
			MIN	TYP	MAX	MIN	MAX	MIN	MAX	
t _{PLH} t _{PHL}	Propagation delay Dna, Dnb, Dnc to Qn	Waveform 1	2.0 1.0	3.5 2.5	5.0 4.5	1.5 1.0	5.5 4.5	1.0 1.0	7.0 5.5	ns

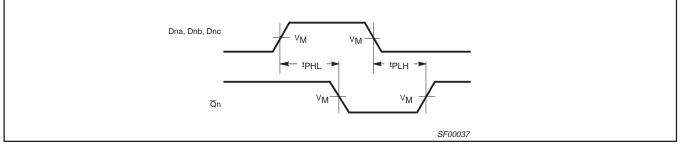
Product specification

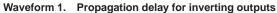
Triple 3-input NOR gate

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SF00006

AC WAVEFORMS

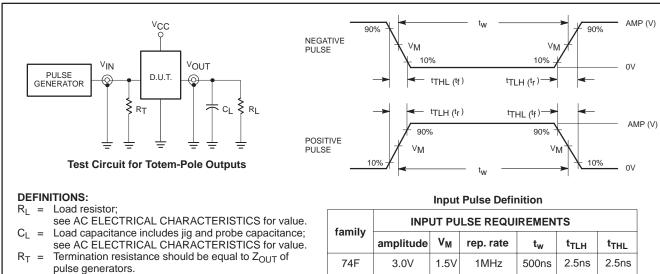


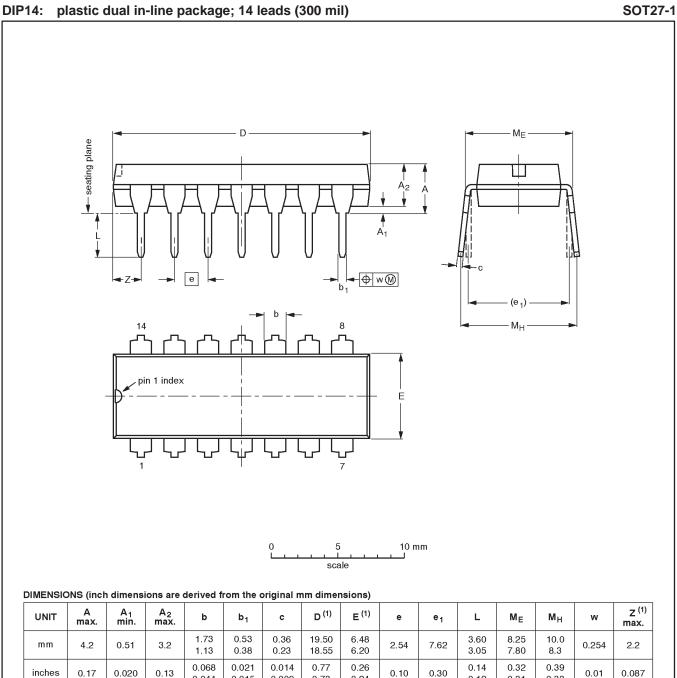


NOTE:

For all waveforms, $V_M = 1.5V$.

TEST CIRCUIT AND WAVEFORMS





Note

1. Plastic or metal protrusions of 0.25 mm maximum per side are not included.

0.044

0.015

0.009

OUTLINE		REFER	EUROPEAN	ISSUE DATE		
VERSION	IEC	JEDEC	EIAJ		PROJECTION	ISSUE DATE
SOT27-1	050G04	MO-001AA				-92-11-17 95-03-11

0.24

0.12

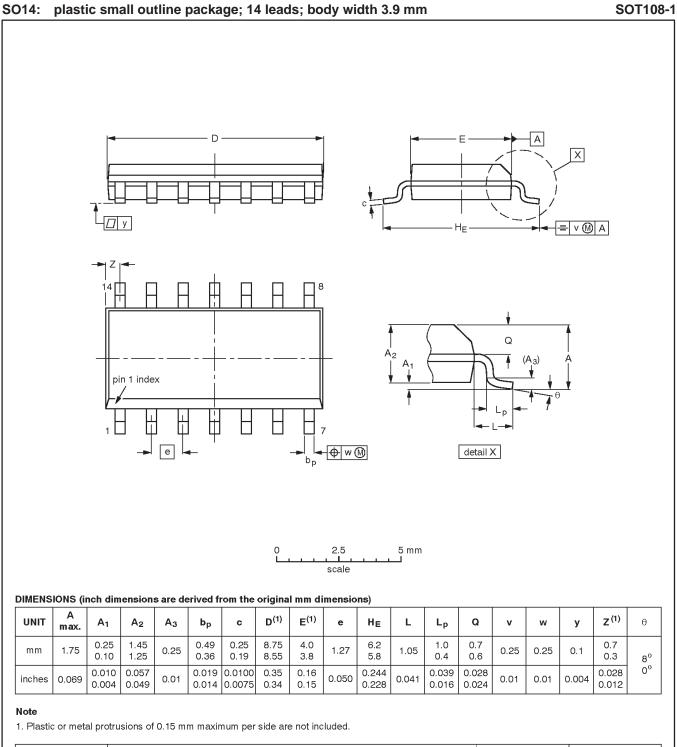
0.31

0.33

0.73

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OUTLINE	REFERENCES				EUROPEAN	ISSUE DATE
VERSION	IEC	JEDEC	EIAJ		PROJECTION	ISSUE DATE
SOT108-1	076E06S	MS-012AB				95-01-23 97-05-22

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Data sheet status

Data sheet status	Product status	Definition ^[1]
Objective specification	Development	This data sheet contains the design target or goal specifications for product development. Specification may change in any manner without notice.
Preliminary specification	Qualification	This data sheet contains preliminary data, and supplementary data will be published at a later date. Philips Semiconductors reserves the right to make chages at any time without notice in order to improve design and supply the best possible product.
Product specification	Production	This data sheet contains final specifications. Philips Semiconductors reserves the right to make changes at any time without notice in order to improve design and supply the best possible product.

[1] Please consult the most recently issued datasheet before initiating or completing a design.

Definitions

Short-form specification — The data in a short-form specification is extracted from a full data sheet with the same type number and title. For detailed information see the relevant data sheet or data handbook.

Limiting values definition — Limiting values given are in accordance with the Absolute Maximum Rating System (IEC 134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of the specification is not implied. Exposure to limiting values for extended periods may affect device reliability.

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